INFORMATION DISCLOSURE CITATION

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Docket Number (Optional) **Application Number** YOR920010104US 4370) Unassigned Applicant(s)

Steven R. Fox, et al. Filing Date Group Art Unit Herewith Unassigned

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				U.S. PATENT DOCUMENTS				
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	ı	DATE OPRIATE
RP		6,090,689	07/18/00	Sadana, et al.			010	
27		6,043,166	03/28/00	Roitman, et al.			884670	
RP		5,930,643	07/27/99			9	·==:	
	_	5,589,407	12/31/96	Meyappan, et al.) 1.0 ()	
		5,519,336	05/21/96	Liu, et al.				
\top		5,288,650	02/22/94	Sandow				
		5,279,978	01/18/94	See, et al.				
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ı	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	YES YES	no No
RP		JP 63 217657	09/09/88	Japan				
	-							
		<u> </u>				***************************************		

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) Wolf, S., "Silicon Processing for the VLSI ERA", Vol. 2: Process Integration, 1990, pp. 72-73

White, A.E., et al., "The role of implant temperature in the formation of thin buried oxide layers", BEAM-SOLID INTERACTIONS AND TRANSIENT PROCESSES SYMPOSIUM, BOSTON, MA, USA, 1-4 DEC. 1986, pp. 585-590, XP000922701

DATE CONSIDERED **EXAMINER**

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.